TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSⅢ)

SSM6J50TU

High Current Switching Applications

Unit: mm

• Compact package suitable for high-density mounting

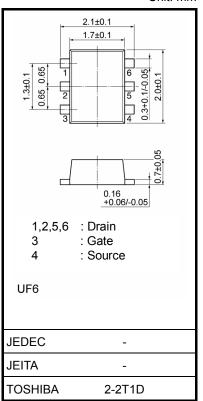
• Low on-resistance: $R_{on} = 205 \text{m}\Omega \text{ (max) } (@V_{GS} = -2.0 \text{ V})$

 $R_{on} = 100 \text{m}\Omega \text{ (max) (@V_{GS} = -2.5 V)}$ $R_{on} = 64 \text{m}\Omega \text{ (max) (@V_{GS} = -4.5 V)}$

Absolute Maximum Ratings (Ta = 25°C)

| Characteristics | | Symbol | Rating | Unit | |
|---------------------------|-------|----------------------------|---------|------|--|
| Drain-Source voltage | | V_{DS} | -20 | V | |
| Gate-Source voltage | | V _{GSS} | ±10 | V | |
| Drain current | DC | ID | -2.5 | А | |
| | Pulse | I _{DP} | -5 | | |
| Drain power dissipation | | P _D (Note 1) | 500 | mW | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | -55~150 | °C | |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e.



Weight: 7 mg (typ.)

operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

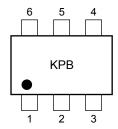
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

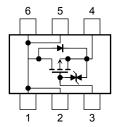
Note 1: Mounted on FR4 board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu Pad: } 645 \text{ mm}^2)$

Marking

Equivalent Circuit





Handling Precaution

When handling individual devices that are not yet mounted on a circuit board, be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

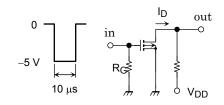
Electrical Characteristics (Ta = 25°C)

| Chara | acteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--------------------------------|---------------|--|---|------|------|------|------|
| Gate leakage cur | rent | I _{GSS} | $V_{GS} = \pm 8 \text{ V}, V_{DS} = 0$ | _ | _ | ±10 | μА |
| Drain-Source breakdown voltage | V (BR) DSS | $I_D = -10 \text{ mA}, V_{GS} = 0$ | -20 | _ | _ | V | |
| | V (BR) DSX | $I_D = -10 \text{ mA}, V_{GS} = +10 \text{ V}$ | -10 | _ | _ | V | |
| Drain cut-off curre | ent | I _{DSS} | $V_{DS} = -20 \text{ V}, V_{GS} = 0$ | _ | _ | -10 | μА |
| Gate threshold vo | oltage | V _{th} | $V_{DS} = -10 \text{ V}, I_D = -0.2 \text{ mA}$ | -0.5 | _ | -1.2 | V |
| Forward transfer | admittance | Y _{fs} | $V_{DS} = -10 \text{ V}, I_D = -1.5 \text{ A}$ (Note2) | 3.1 | 6.2 | _ | S |
| Drain-Source on-resistance | | R _{DS} (ON) | $I_D = -1.5 \text{ A}, V_{GS} = -4.5 \text{ V}$ (Note2) | _ | 49 | 64 | - mΩ |
| | | | $I_D = -1.5 \text{ A}, V_{GS} = -2.5 \text{ V}$ (Note2) | _ | 73 | 100 | |
| | | | $I_D = -1.5 \text{ A}, V_{GS} = -2.0 \text{ V}$ (Note2) | _ | 105 | 205 | |
| Input capacitance | | C _{iss} | $V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$ | | 800 | _ | pF |
| Reverse transfer capacitance | | C _{rss} | V _{DS} = -10 V, V _{GS} = 0, f = 1 MHz | | 120 | _ | pF |
| Output capacitance | | Coss | $V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$ | _ | 160 | _ | pF |
| Switching time | Turn-on time | t _{on} | $V_{DD} = -10 \text{ V}, I_D = -1.5 \text{ A},$ | _ | 15 | _ | ns |
| | Turn-off time | t _{off} | $V_{GS} = 0 \sim -5 \text{ V}, R_G = 4.7 \Omega$ | _ | 51 | _ | |

Note2: Pulse test

Switching Time Test Circuit





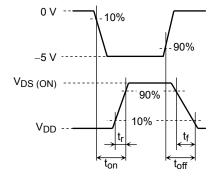
$$\begin{split} &V_{DD} = \text{-}10 \text{ V} \\ &R_G = 4.7 \text{ }\Omega \\ &\text{D.U.} \le 1\% \\ &V_{IN}\text{: }t_r, t_f < 5 \text{ ns} \end{split}$$

Common Source

 $Ta = 25^{\circ}C$

(b) V_{IN}

(c) V_{OUT}

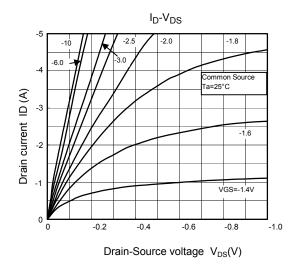


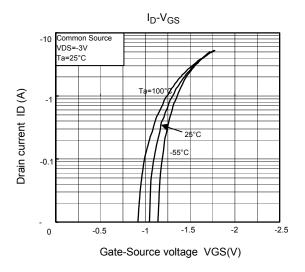
Precaution

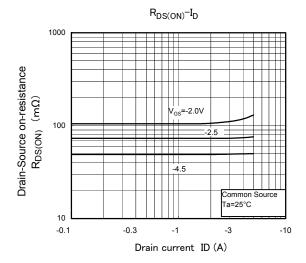
 V_{th} can be expressed as the voltage between gate and source when the low operating current value is I_D =-200 μA for this product. For normal switching operation, $V_{GS\ (on)}$ requires a higher voltage than V_{th} and $V_{GS\ (off)}$ requires a lower voltage than V_{th} .

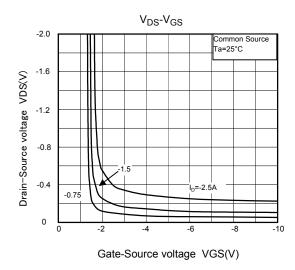
(The relationship can be established as follows: $V_{GS (off)} < V_{th} < V_{GS (on)}$)

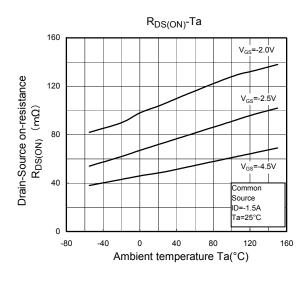
Be sure to take this into consideration when using the device.

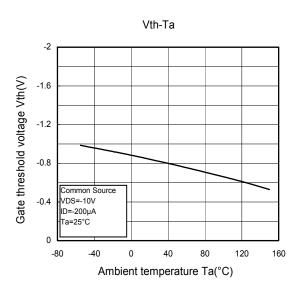


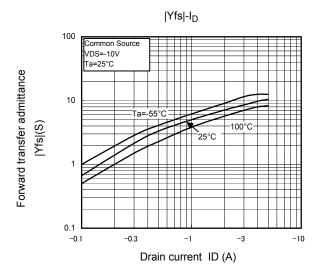


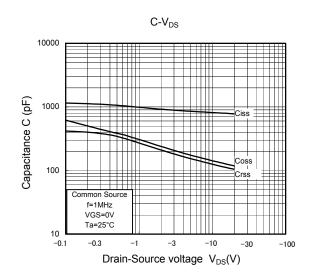


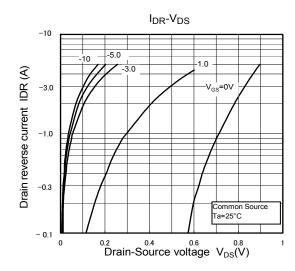


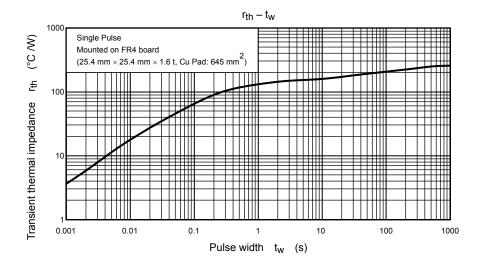


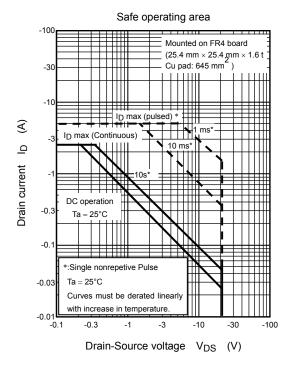


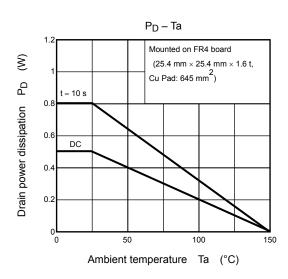












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20070701-EN GENERAL

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